



RF IC Technologies and Devices

Brief review on RF IC technologies

- MOS technology
- Passive devices
- Bonding
- Self-learning assignment 2

Exercises & Homework

- CAD exercise
- Homeworks

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RF IC Technologies

Gallium Arsenide

- MESFET
- HEMT
- HBT

GaAs technologies have no or poor p-type FETs \rightarrow no complementary devices \rightarrow no good digital logic

Silicon / SiGe

- BJT
- BiCMOS
- CMOS

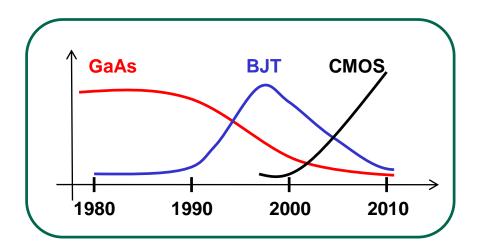
Rare technologies for very high speed or power

- InP
- GaN
- SiC

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RF IC designing has and will change ...



Trends:

- Technology
 - GaAs → Si BJT → BiCMOS → bulk CMOS → FD-SOI & Finfet CMOS
- Design complexity
 - Circuit \rightarrow Block \rightarrow RX-TX-SX \rightarrow multi-system, SOC, SDR
- Design paradigm:
 - RF engineering \rightarrow RF IC design \rightarrow Multi-mode design
- Designers
 - Spesialists \rightarrow in-house groups \rightarrow fabless & foundry groups

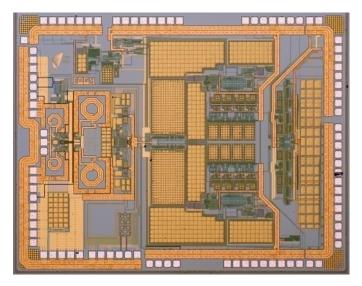


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Typical RF CMOS Process

- Gate lenght: 65 nm \rightarrow 40 nm \rightarrow **28 nm** \rightarrow 14 nm \rightarrow 10 nm \rightarrow 7...5 ... 3 nm
- Typical device f_t 100-300 GHz
- 6-10 metal layers (copper or aluminium)
- NMOS & PMOS devices
 - 2-3 threshold voltage (V_T) levels
 - Specific RF devices = RF model & layout
 - Core devices simpler (model & layout)
- Passive devices with RF model
 - Inductors and transformers
 - Capacitors (MIM)
 - Varactors (MOS & pn)
 - Resistors (poly-silicon, 2-3 different R_{sa})
- Digital cell libraries (VHDL \rightarrow compiler)



Modern CMOS technology is very versatile and good for RF ICs. Critical practical challenge is the quality (and availability) of device **MODELS.**

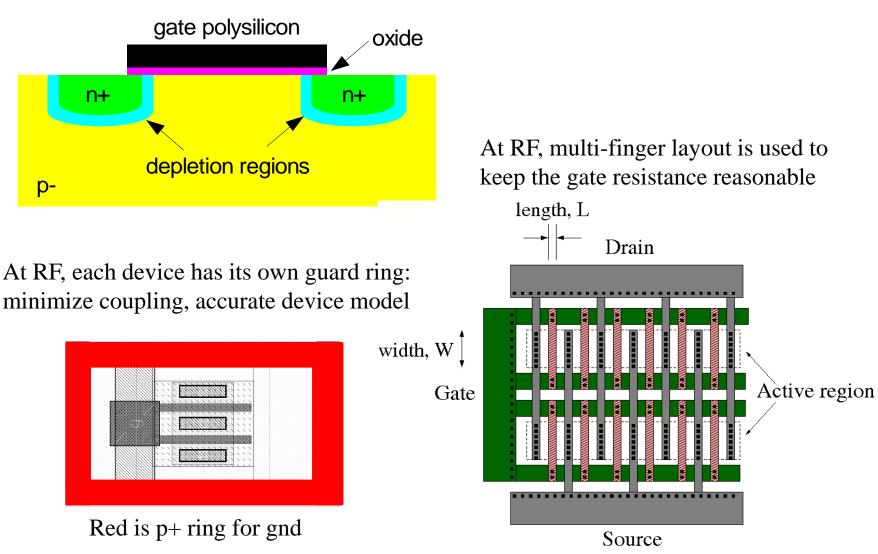


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NMOS Device

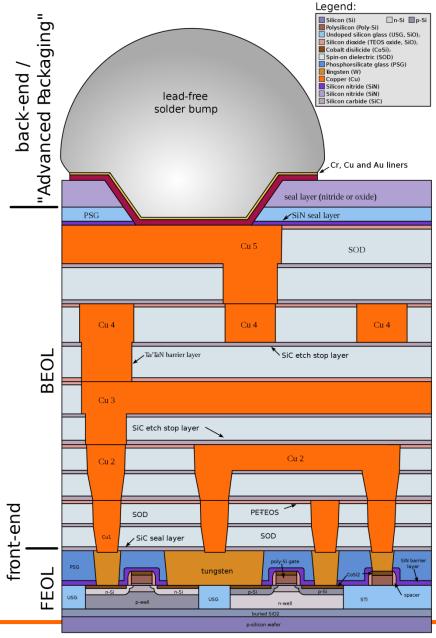




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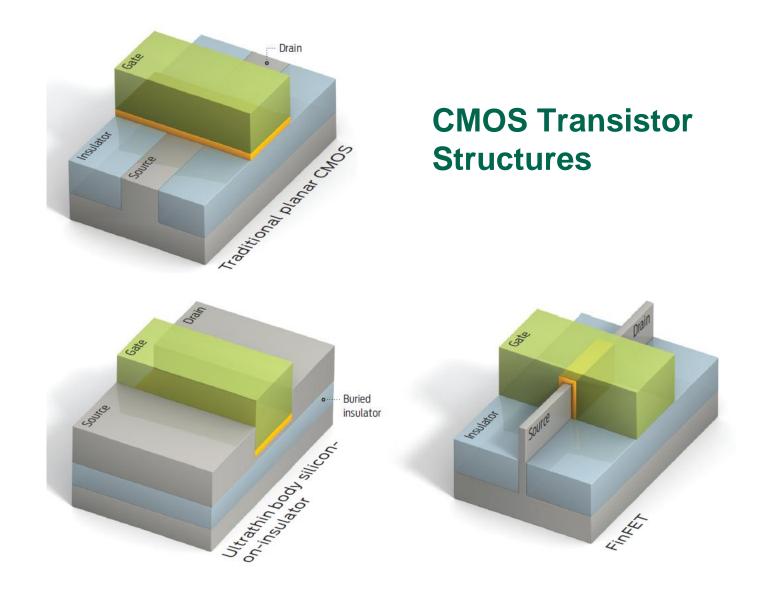
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CMOS Cross-Section



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Engineering



Ahmed, K.; Schuegraf, K.; "Transistor wars," IEEE Spectrum, vol. 48, no.11, pp.50-66, Nov 2011



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FD-SOI and FinFET Technologies

A video on FD-SOI by ST Microelectronics

https://www.youtube.com/watch?v=uvV7jcpQ7UY

A video on FinFET by ThresholdSystems

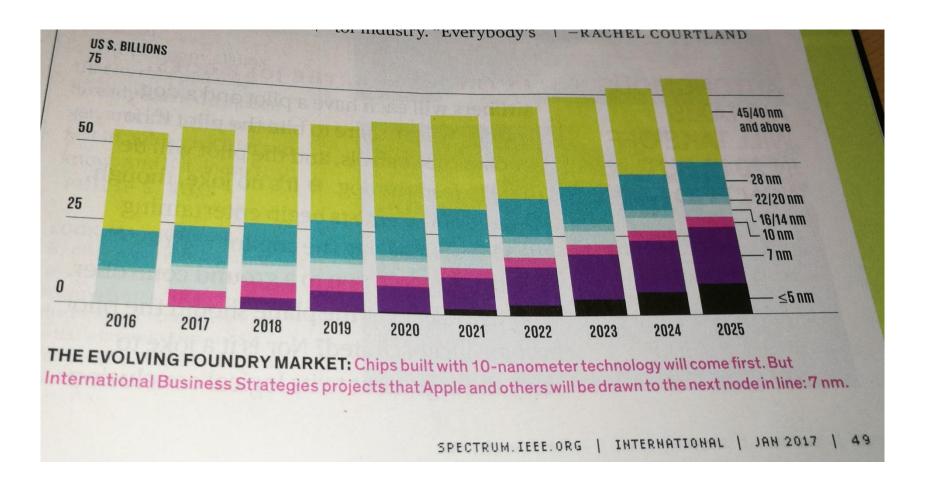
https://www.youtube.com/watch?v=c-3p8moNXfI&t=0s

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Moore's law has hold well



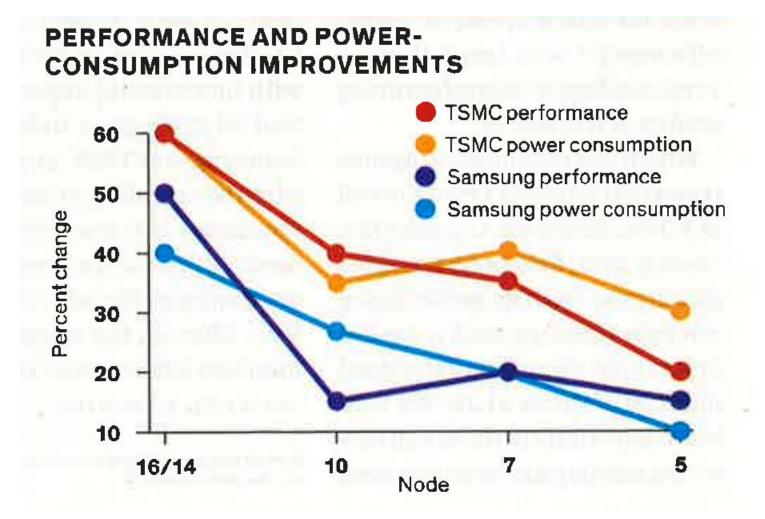


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But the impact is slowing down



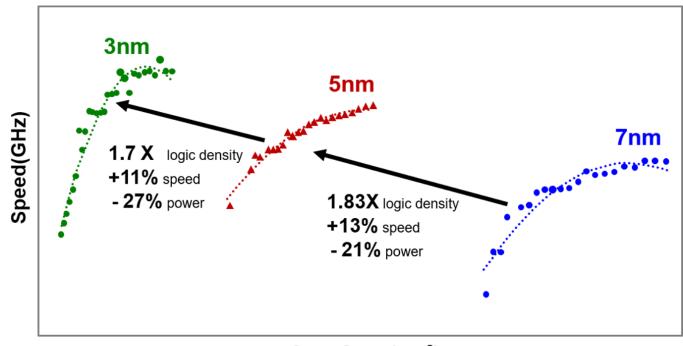
Rumors: Intel is still struggling with 14nm node, and GF will stay at 14nm.



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Mark Liu, Taiwan Semiconductor Manufacturing Company, at ISSCC 2021



Core Area (µm²)



Passive Devices in RF CMOS process

- 1. Resistor
- 2. Inductor
- 3. Transmission line
- 4. Capacitor
- 5. MOS varactor
- 6. SC network
- 7. Bonding pad
- 8. Wire bonding
- 9. Flip-chip (BGA)



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Quality Factor Q

Quality factor Q is a metric to describe the losses of reactive component BUT, it is also used in filter design to define the steepness of your filter \rightarrow A risk to a confusion.

- Q=10, low-quality passive such as on-chip coil
- Q=100, already close to ideal in most cases
- Q>1000, losses play role only in special cases



Quality Factor Q

The most general definition of the Q-factor is based on the ratio of stored energy to dissipated energy per cycle:

$$Q = \frac{E_{store}}{E_{diss} / \omega}$$

For an ideal inductor with a series resistor R, we have

$$Q = \omega \frac{\frac{1}{2}Li^2}{\frac{1}{2}Ri^2} = \frac{\omega L}{R}$$

Alternative definition is based on 3-dB bandwidth of a resonator / filter

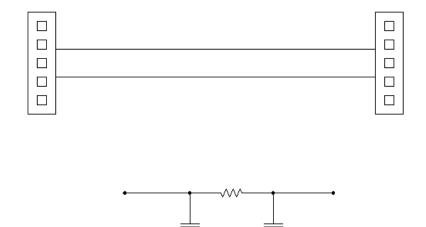
$$Q_{3dB} = \frac{\omega_0}{\Delta \omega_{3dB}}$$

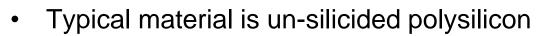
Now, consider an ideal (lossless) LC-bandpass filter: Q is infinite, Q_{3dB} is real.

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Integrated Resistor





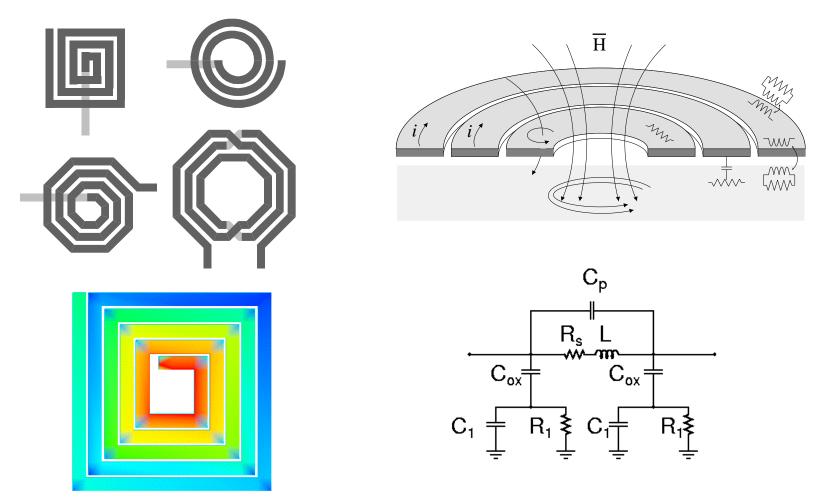
- Sheet resistance typ. 100-300 Ω
- Quite small parasitic capacitance, OK for RF ICs
- Process variation significant, typ. 20-50 %
- "well"-type silicon resistors not good for RF; High Cpar



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Monolithic Inductor

Very important for RF ICs \rightarrow Self-learning assignment



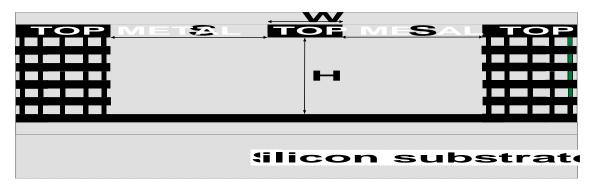


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Integrated Transmission Line

Microstrip line $h \ll s$

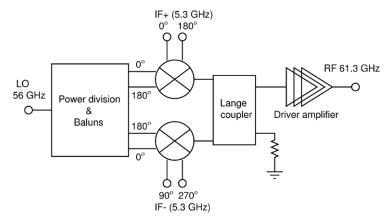


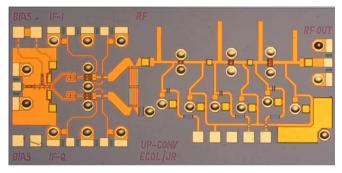
Coplanar waveguide (CPW)

TOPMETAL	TOP	MESA	L TOP
	41100		
		nsuk	ostrate



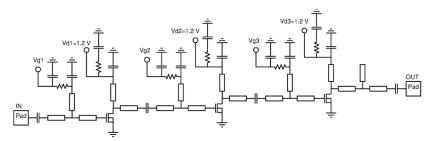
Examples of Transmission Line Circuits

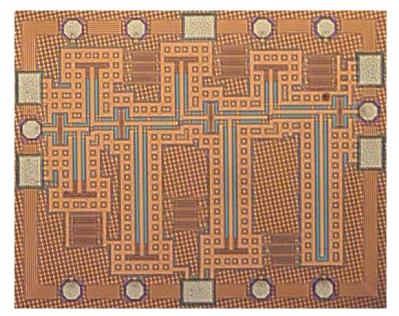




@ Jan Riska

A 60-GHz three stage amplifier

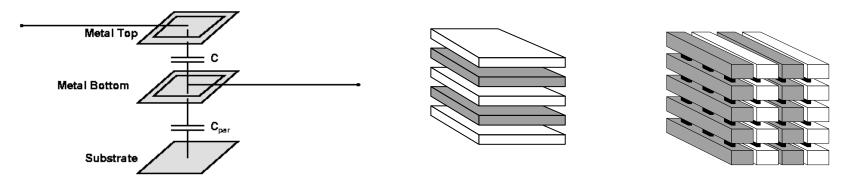




@ Mikko Varonen



Integrated Capacitors



Metal-insulator-metal (MIM)

Sandwich MIM

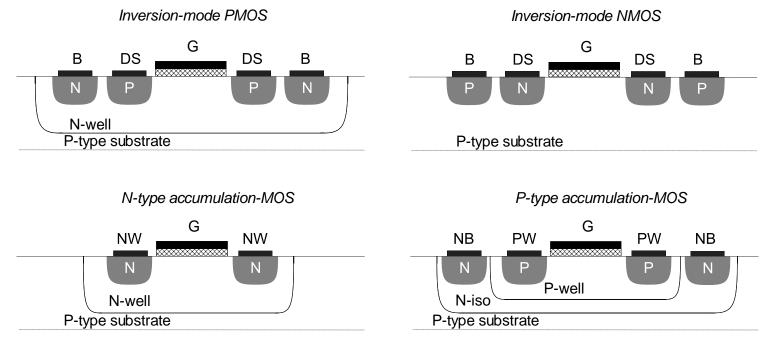
Lateral flux

- Main issues are capacitance density and C/Cpar
- Quality factors are high; take care of interconnections
- In sub-100nm technologies lateral flux caps are better
- Process variation significant, typ. 10-30 %



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MOS varactors

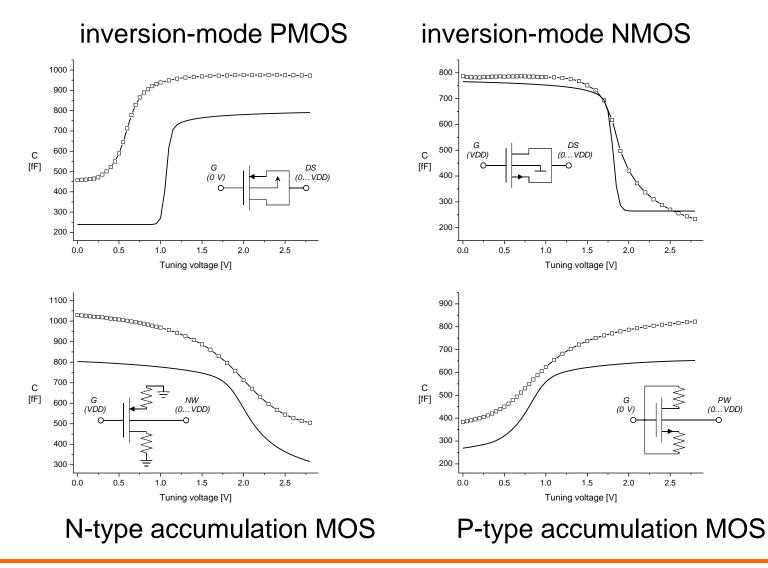


- Four types are available, inversion-mode are "ordinary" MOSFETs
- Quality factor and tuning range (Cmax/Cmin) are competing properties
- Typ. Q~50 at 2 GHz and Cmax/Cmin ~3
- Process variation tracks to MOSFET variation

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MOS Varactors

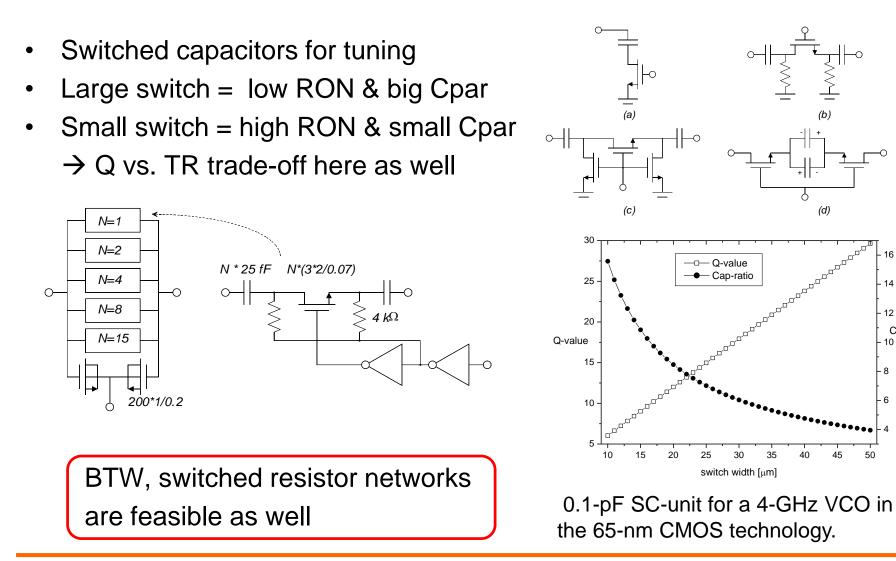


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Switched-Capacitor Network





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16

14

12

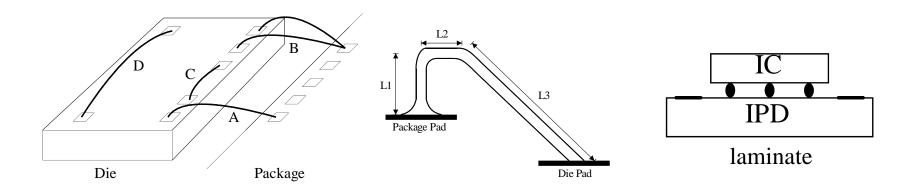
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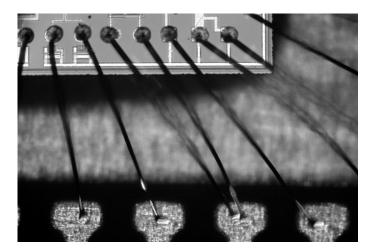
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50

C/Coff

Wire Bonding and Flip-Chip Assembly



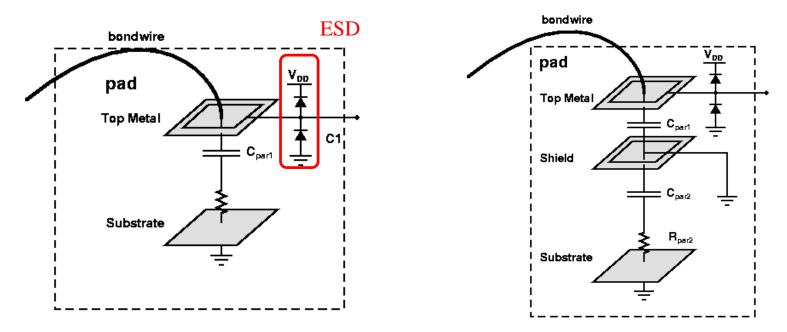


- Bond wire = high-Q inductor, L=1nH / mm, typ. 1-3 mm
- Ball-grid array solder bumb H=100-200 um, Ø~50 um small high-Q inductor
- Flip-chip requires substrate (laminate) and second bonding → modeling !



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Bonding Pad



- Pad produces parasitic capacitance
- ESD protection circuit produces parasitic capacitance
- "RF pad" model needed in a design kit



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Recap

RFIC technologies

- CMOS is the prevalent tech best for mixed mode apps
- SiGe BiCMOS for mmWave applications
- GaN for power amplifiers
- InP for very high frequencies

RFIC components

- Model availability / accuracy is the key question
- Coils are a specialty of RF Ics
- Transmission lines appear at above 50 GHz



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Next Meeting

Topics will be

- concepts related to amplifiers
- low-noise amplifiers
- power amplifiers
- buffers

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Self-Learning Assignment 2

Objectives are to familiarize yourself with properties of **monolithic coils** and transformers



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